

<b>Notice of References Cited</b>	Application/Control No. 10/019,332	Applicant(s)/Patent Under Reexamination SHINO ET AL.	
	Examiner Danny Wai Lun Leung	Art Unit 2633	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	D	US-			
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	K	US-			
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	N					
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**NON-PATENT DOCUMENTS**

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